Search Notes		

Application/Control No.		Applicant(s)/Pate Reexamination	Applicant(s)/Patent under Reexamination	
10/615,021		CHANG, WON-	KIL	
Examiner		Art Unit		
Shih-wen Hsiel	h	2861		

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	SEAR	CHED	
Class	Subclass	Date	Examiner
347	1,22,29 30,32,33 81	5/19/2005	swh
15	250.361	5/19/2005	SWH
101	155	5/19/2005	swh
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
347	33	5/19/2005	swн
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SEARCH (INCLUDING SEA		SY)
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